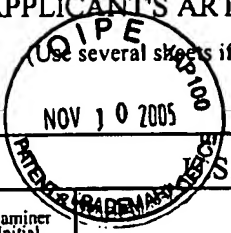
		Application 10/526,831		OFGS File No. P/1805-17			
		Applicant Markus Turtinen, et al.					
		Filing Date July 20, 2005		Group Art Unit 2856			
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
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	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
/T.R./		European Search Report dated March 12, 2007					
/T.R./		Jukka Iivarinen, et al. (1996) Unsupervised Segmentation of Surface Defects, IEEE, pp. 1015-4651.					
/Thomas Redding/ Examiner		09/24/2007 Date Considered					
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FOREIGN PATENT DOCUMENTS						
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/T.R./		Jukka Iivarinen (2000) Surface Defect Detection with Histogram-Based Texture Features, Helsinki University of Technology, Laboratory of Computer and Information Science.				
/T.R./		Jukka Iivarinen, et al. (1998) An Adaptive Texture and Shape Based Defect Classification, Pattern Recognition, Proceedings, PP. 117-122.				
/T.R./		Timo Ojala, et al., Gray Scale and Rotation Invariant Texture Classification with Local Binary Patterns, IEEE Transactions on Pattern Analysis and Machine Intelligence, Vol. 24, No. 7.				
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/T.R./	10318937	12-1998	Japan			X
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/T.R./		Jukka Iivarinen, <i>An Adaptive Texture and Shape Based Defect Classification</i> , Fourteenth International Conference on Pattern Recognition, Brisbane, Australia, August 1998.				
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
/T.R./	10318937 A	12-1998	Japan			Abstract	
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/T.R./	"An Adaptive Texture and Shape Based Defect Classification" by Jukka Iivarinen et al., 1998.						
/T.R./	"Content-Based Image Retrieval in Surface Inspection" by Jukka Iivarinen et al., 2002.						
/T.R./	"HIERARCHICAL Neural Network for COLOR Classification" by A. Verikas et al., 1994.						
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